# **ANALOG DEVICES**

# Low Capacitance, Low Charge Injection, $\pm 15 \text{ V/} \pm 12 \text{ V} i \text{CMOS}^{\text{TM}}$ Quad SPST Switches

# ADG1211/ADG1212/ADG1213

#### FEATURES

1 pF off capacitance 2.6 pF on capacitance <1 pC charge injection 33 V supply range 120 Ω on resistance Fully specified at ±15 V, +12 V No V<sub>L</sub> supply required 3 V logic-compatible inputs Rail-to-rail operation 16-lead TSSOP and 16-lead LFCSP Typical power consumption: <0.03 μW

#### APPLICATIONS

Automatic test equipment Data acquisition systems Battery-powered systems Sample-and-hold systems Audio signal routing Video signal routing Communication systems

### **GENERAL DESCRIPTION**

The ADG1211/ADG1212/ADG1213 are monolithic complementary metal-oxide semiconductor (CMOS) devices containing four independently selectable switches designed on an *i*CMOS (industrial CMOS) process. *i*CMOS is a modular manufacturing process combining high voltage CMOS and bipolar technologies. It enables the development of a wide range of high performance analog ICs capable of 33 V operation in a footprint that no previous generation of high voltage parts has been able to achieve. Unlike analog ICs using conventional CMOS processes, *i*CMOS components can tolerate high supply voltages while providing increased performance, dramatically lower power consumption, and reduced package size.

The ultralow capacitance and charge injection of these switches make them ideal solutions for data acquisition and sample-andhold applications, where low glitch and fast settling are required. Fast switching speed coupled with high signal bandwidth make the parts suitable for video signal switching.

### FUNCTIONAL BLOCK DIAGRAM

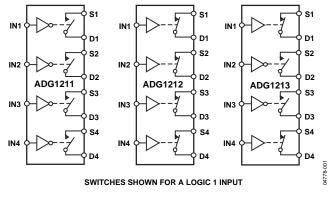


Figure 1.

*i*CMOS construction ensures ultralow power dissipation, making the parts ideally suited for portable and battery-powered instruments.

The ADG1211/ADG1212/ADG1213 contain four independent single-pole/single-throw (SPST) switches. The ADG1211 and ADG1212 differ only in that the digital control logic is inverted. The ADG1211 switches are turned on with Logic 0 on the appropriate control input, while Logic 1 is required for the ADG1212. The ADG1213 has two switches with digital control logic similar to that of the ADG1211; the logic is inverted on the other two switches. The ADG1213 exhibits break-beforemake switching action for use in multiplexer applications.

Each switch conducts equally well in both directions when on and has an input signal range that extends to the supplies. In the off condition, signal levels up to the supplies are blocked.

#### **PRODUCT HIGHLIGHTS**

- 1. Ultralow capacitance.
- 2. <1 pC charge injection.
- 3. 3 V logic-compatible digital inputs:  $V_{IH} = 2.0$  V,  $V_{IL} = 0.8$  V.
- 4. No V<sub>L</sub> logic power supply required.
- 5. Ultralow power dissipation:  $<0.03 \mu$ W.
- 6. 16-lead TSSOP and 3 mm  $\times$  3 mm LFCSP packages.

Rev. 0

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### **REVISION HISTORY**

7/05—Revision 0: Initial Version

### **SPECIFICATIONS**

### **DUAL SUPPLY**

 $V_{\text{DD}}$  = 15 V  $\pm$  10%,  $V_{\text{SS}}$  = –15 V  $\pm$  10%, GND = 0 V, unless otherwise noted.

### Table 1.

Parameter	25°C	Y Version <sup>1</sup> -40°C to +85°C	–40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			$V_{DD}$ to $V_{SS}$	V	
On Resistance (R <sub>ON</sub> )	120			Ωtyp	$V_{s} = \pm 10 V$ , $I_{s} = -1 mA$ ; Figure 20
	190	230	260	Ωmax	$V_{DD} = +13.5 \text{ V}, V_{SS} = -13.5 \text{ V}$
On Resistance Match Between Channels ( $\Delta R_{ON}$ )	2.5			Ωtyp	$V_{s} = \pm 10 V$ , $I_{s} = -1 mA$
	6	10	11	Ωmax	
On Resistance Flatness (R <sub>FLAT(ON</sub> ))	20			Ωtyp	$V_s = -5 V/0 V/+5 V$ ; $I_s = -1 mA$
	57	72	79	Ωmax	
LEAKAGE CURRENTS					$V_{DD} = +16.5 \text{ V}, V_{SS} = -16.5 \text{ V}$
Source Off Leakage, Is (Off)	±0.02			nA typ	$V_s = \pm 10 \text{ V}, V_D = \mp 10 \text{ V};$ Figure 21
	±0.1	±0.6	±1	nA max	_
Drain Off Leakage, I <sub>D</sub> (Off)	±0.02			nA typ	$V_s = \pm 10 V$ , $V_D = \mp 10 V$ ; Figure 21
	±0.1	±0.6	±1	nA max	
Channel On Leakage, I <sub>D</sub> , I <sub>S</sub> (On)	±0.02			nA typ	$V_{s} = V_{D} = \pm 10 V$ ; Figure 22
<b>9</b> • • • •	±0.1	±0.6	±1	nA max	
DIGITAL INPUTS					
Input High Voltage, VINH			2.0	V min	
Input Low Voltage, V <sub>INL</sub>			0.8	V max	
Input Current, IINL or IINH	0.005			μA typ	$V_{IN} = V_{INL} \text{ or } V_{INH}$
			±0.1	μA max	
Digital Input Capacitance, C <sub>IN</sub>	2.5			pF typ	
DYNAMIC CHARACTERISTICS <sup>2</sup>					
ton	105			ns typ	$R_L = 300 \Omega$ , $C_L = 35 pF$
	125	160	185	ns max	$V_s = 10 V$ ; Figure 23
toff	40			ns typ	$R_L = 300 \Omega$ , $C_L = 35 pF$
	50	60	60	ns max	V <sub>s</sub> = 10 V; Figure 23
Break-Before-Make Time Delay, t <sub>D</sub>	25			ns typ	$R_L = 300 \ \Omega$ , $C_L = 35 \ pF$
(ADG1213 Only)			10	ns min	$V_{S1} = V_{S2} = 10 V$ ; Figure 24
Charge Injection	-0.3			pC typ	$V_s = 0 V$ , $R_s = 0 \Omega$ , $C_L = 1 nF$ ; Figure 25
Off Isolation	80			dB typ	$R_L = 50 \Omega$ , $C_L = 5 pF$ , $f = 1 MHz$ ; Figure 26
Channel-to-Channel Crosstalk	90			dB typ	$R_{\text{L}}=50~\Omega,$ $C_{\text{L}}=5~\text{pF},$ $f=1~\text{MHz};$ Figure 27
Total Harmonic Distortion + Noise	0.15			% typ	$R_L = 10 \text{ k}\Omega$ , 5 V rms, f = 20 Hz to 20 kHz
–3 dB Bandwidth	1000			MHz typ	$R_L = 50 \Omega$ , $C_L = 5 pF$ ; Figure 28
C <sub>s</sub> (Off)	0.9			pF typ	$V_{s} = 0 V, f = 1 MHz$
	1.1			pF max	$V_s = 0 V, f = 1 MHz$
C <sub>D</sub> (Off)	1			pF typ	$V_{s} = 0 V, f = 1 MHz$
	1.2			pF max	$V_s = 0 V, f = 1 MHz$
C <sub>D</sub> , C <sub>s</sub> (On)	2.6			pF typ	$V_s = 0 V, f = 1 MHz$
	3			pF max	$V_s = 0 V, f = 1 MHz$

	Y Version <sup>1</sup>				
Parameter	25°C	-40°C to +85°C	–40°C to +125°C	Unit	Test Conditions/Comments
POWER REQUIREMENTS					$V_{DD} = +16.5 \text{ V}, \text{ V}_{SS} = -16.5 \text{ V}$
I <sub>DD</sub>	0.001			μA typ	Digital inputs = $0 V \text{ or } V_{DD}$
			1.0	μA max	
I <sub>DD</sub>	220			μA typ	Digital inputs = 5 V
			320	μA max	
Iss	0.001			μA typ	Digital inputs = $0 V \text{ or } V_{DD}$
			1.0	μA max	
Iss	0.001			μA typ	Digital inputs = 5 V
			1.0	μA max	

 $^1$  Temperature range for Y version is  $-40^\circ C$  to  $+125^\circ C.$   $^2$  Guaranteed by design, not subject to production test.

### SINGLE SUPPLY

 $V_{\text{DD}}$  = 12 V  $\pm$  10%,  $V_{\text{SS}}$  = 0 V, GND = 0 V, unless otherwise noted.

#### Table 2.

		Y Version <sup>1</sup> –40°C to	–40°C to		
Parameter	25°C	+85°C	+125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			0 V to V <sub>DD</sub>	V	
On Resistance (R <sub>ON</sub> )	300			Ω typ	$V_s = 0 V$ to 10 V, $I_s = -1 mA$ ; Figure 20
	475	567	625	Ωmax	$V_{DD} = 10.8 V, V_{SS} = 0 V$
On Resistance Match Between Channels (ΔR <sub>ON</sub> )	4.5			Ωtyp	$V_{s} = 0 V to 10 V, I_{s} = -1 mA$
	12	26	27	Ωmax	
On Resistance Flatness (R <sub>FLAT(ON)</sub> )	60			Ωtyp	$V_s = 3 V/6 V/9 V$ , $I_s = -1 mA$
LEAKAGE CURRENTS					$V_{DD} = 13.2 \text{ V}, \text{ V}_{SS} = 0 \text{ V}$
Source Off Leakage, Is (Off)	±0.02			nA typ	$V_{s} = 1 \text{ V}/10 \text{ V}, V_{D} = 10 \text{ V}/1 \text{ V};$ Figure 21
	±0.1	±0.6	±1	nA max	
Drain Off Leakage, I <sub>D</sub> (Off)	±0.02			nA typ	$V_{s} = 1 \text{ V}/10 \text{ V}, V_{D} = 10 \text{ V}/1 \text{ V};$ Figure 21
-	±0.1	±0.6	±1	nA max	
Channel On Leakage, I <sub>D</sub> , I <sub>S</sub> (On)	±0.02			nA typ	$V_s = V_D = 1 V \text{ or } 10 V$ ; Figure 22
-	±0.1	±0.6	±1	nA max	
DIGITAL INPUTS					
Input High Voltage, V <sub>INH</sub>			2.0	V min	
Input Low Voltage, VINL			0.8	V max	
Input Current, linl or linh	0.001			μA typ	$V_{IN} = V_{INL} \text{ or } V_{INH}$
			±0.1	µA max	
Digital Input Capacitance, C <sub>№</sub>	3			pF typ	
DYNAMIC CHARACTERISTICS <sup>2</sup>	-			r yr	
ton	120			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
- Cont	155	190	225	ns max	$V_{\rm s} = 8 \text{ V};$ Figure 23
toff	45			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	65	75	85	ns max	$V_{\rm s} = 8 V;$ Figure 23
Break-Before-Make Time Delay, t <sub>D</sub>	50	, 5	00	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
(ADG1213 Only)	50		10	ns min	$V_{s1} = V_{s2} = 8$ V; Figure 24
Charge Injection	0		10	pC typ	$V_{s} = 6 V, R_{s} = 0 \Omega, C_{L} = 1 nF;$ Figure 25
Off Isolation	80			dB typ	$R_L = 50 \Omega$ , $C_L = 5 pF$ , $f = 1 MHz$ ; Figure 26
Channel-to-Channel Crosstalk	90			dB typ	$R_L = 50 \Omega_2$ , $C_L = 5 \text{ pF}$ , $f = 1 \text{ MHz}$ ; Figure 27 $R_L = 50 \Omega$ , $C_L = 5 \text{ pF}$ , $f = 1 \text{ MHz}$ ; Figure 27
–3 dB Bandwidth	900 900			MHz typ	$R_L = 50 \Omega_2, C_L = 5 \text{ pF}; F = 1 \text{ Min}_2, F \text{ gure } 27$ $R_L = 50 \Omega, C_L = 5 \text{ pF}; F \text{ Figure } 28$
Cs (Off)	1.2			pF typ	$V_s = 6 V, f = 1 MHz$
	1.4				$V_{s} = 6 V, f = 1 MHz$
C <sub>D</sub> (Off)				pF max	$V_{s} = 6V, f = 1 MHz$
	1.3			pF typ	$V_{s} = 6 V, I = 1 MHZ$ $V_{s} = 6 V, f = 1 MHZ$
$C \left( \left( 0 \right) \right)$	1.5			pF max	$V_{s} = 6 V, f = 1 MHZ$ $V_{s} = 6 V, f = 1 MHZ$
C <sub>D</sub> , C <sub>s</sub> (On)	3.2			pF typ	
	3.9			pF max	$V_s = 6 V, f = 1 MHz$
POWER REQUIREMENTS	0.001				$V_{DD} = 13.2 V$
I <sub>DD</sub>	0.001		1.0	μA typ	Digital inputs = $0 \text{ V or } V_{DD}$
			1.0	μA max	
I <sub>DD</sub>	220			μA typ	Digital inputs = 5 V
			320	μA max	

 $^1$  Temperature range for Y version is –40°C to +125°C.  $^2$  Guaranteed by design, not subject to production test.

### **ABSOLUTE MAXIMUM RATINGS**

 $T_A = 25^{\circ}C$ , unless otherwise noted.

Table 3.	
Parameter	Rating
V <sub>DD</sub> to V <sub>SS</sub>	35 V
V <sub>DD</sub> to GND	–0.3 V to +25 V
V <sub>ss</sub> to GND	+0.3 V to -25 V
Analog Inputs <sup>1</sup>	V <sub>ss</sub> – 0.3 V to V <sub>DD</sub> + 0.3 V or 30 mA, whichever occurs first
Digital Inputs <sup>1</sup>	GND – 0.3 V to V <sub>DD</sub> + 0.3 V or 30 mA, whichever occurs first
Peak Current, S or D	100 mA (pulsed at 1 ms, 10% duty cycle max)
Continuous Current per Channel, S or D	25 mA
Operating Temperature Range	
Automotive (Y Version)	–40°C to +125°C
Storage Temperature Range	–65°C to +150°C
Junction Temperature	150°C
16-Lead TSSOP, θJA Thermal Impedance (4-Layer Board)	112°C/W
16-Lead LFCSP, θ <sub>JA</sub> Thermal Impedance	72.7°C/W
Reflow Soldering Peak Temperature, Pb free	260°C

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Only one absolute maximum rating may be applied at any one time.

#### Table 4. ADG1211/ADG1212 Truth Table

ADG1211 INx	ADG1212 INx	Switch Condition	
0	1	On	
1	0	Off	

#### Table 5. ADG1213 Truth Table

ADG1213 INx	Switch 1, 4	Switch 2, 3
0	Off	On
1	On	Off

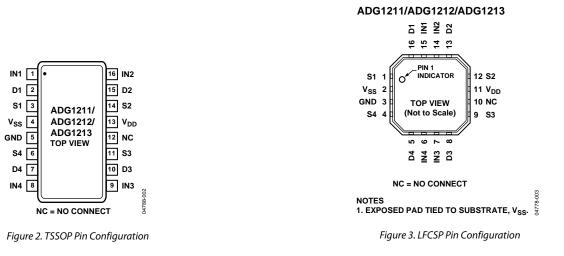
<sup>1</sup> Overvoltages at IN, S, or D are clamped by internal diodes. Current should be limited to the maximum ratings given.

### **ESD CAUTION**

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



### **PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS**



#### **Table 6. Pin Function Descriptions**

Pin No.			
TSSOP	LFCSP	Mnemonic	Description
1	15	IN1	Logic Control Input.
2	16	D1	Drain Terminal. Can be an input or output.
3	1	S1	Source Terminal. Can be an input or output.
4	2	Vss	Most Negative Power Supply Potential.
5	3	GND	Ground (0 V) Reference.
6	4	S4	Source Terminal. Can be an input or output.
7	5	D4	Drain Terminal. Can be an input or output.
8	6	IN4	Logic Control Input.
9	7	IN3	Logic Control Input.
10	8	D3	Drain Terminal. Can be an input or output.
11	9	S3	Source Terminal. Can be an input or output.
12	10	NC	No Connection.
13	11	V <sub>DD</sub>	Most Positive Power Supply Potential.
14	12	S2	Source Terminal. Can be an input or output.
15	13	D2	Drain Terminal. Can be an input or output.
16	14	IN2	Logic Control Input.

### TERMINOLOGY

 $\mathbf{I}_{\text{DD}}$ 

The positive supply current.

Iss The negative supply current.

 $\mathbf{V}_{D}\left(\mathbf{V}s\right)$  The analog voltage on Terminals D and S.

**R**<sub>ON</sub> The ohmic resistance between D and S.

R<sub>FLAT(ON)</sub>

Flatness is defined as the difference between the maximum and minimum value of on resistance, as measured over the specified analog signal range.

Is (Off) The source leakage current with the switch off.

 $I_{\rm D}$  (Off) The drain leakage current with the switch off.

 $\mathbf{I}_{\mathrm{D}}, \mathbf{I}_{\mathrm{S}}\left(\mathbf{On}\right)$  The channel leakage current with the switch on.

 $\label{eq:Vinl} V_{\text{INL}}$  The maximum input voltage for Logic 0.

V<sub>INH</sub> The minimum input voltage for Logic 1.

$$\begin{split} I_{\text{INL}}\left(I_{\text{INH}}\right) \\ \text{The input current of the digital input.} \end{split}$$

### Cs (Off)

The off switch source capacitance, measured with reference to ground.

 $C_D$  (Off) The off switch drain capacitance, measured with reference to ground.  $C_D$ ,  $C_S$  (On)

The on switch capacitance, measured with reference to ground.

C<sub>IN</sub> The digital input capacitance.

**t**<sub>ON</sub> The delay between applying the digital control input and the output switching on. See Figure 23.

**t**<sub>OFF</sub> The delay between applying the digital control input and the output switching off. See Figure 23.

**Charge Injection** A measure of the glitch impulse transferred from the digital input to the analog output during switching.

**Off Isolation** A measure of unwanted signal coupling through an off switch.

#### Crosstalk

A measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.

**Bandwidth** The frequency at which the output is attenuated by 3 dB.

**On Response** The frequency response of the on switch.

**Insertion Loss** The loss due to the on resistance of the switch.

**THD + N** The ratio of the harmonic amplitude plus noise of the signal to the fundamental.

### **TYPICAL PERFORMANCE CHARACTERISTICS**

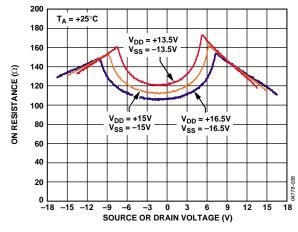


Figure 4. On Resistance as a Function of  $V_D$  ( $V_S$ ) for Dual Supply

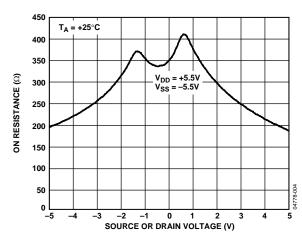


Figure 5. On Resistance as a Function of V<sub>D</sub> (V<sub>s</sub>) for Dual Supply

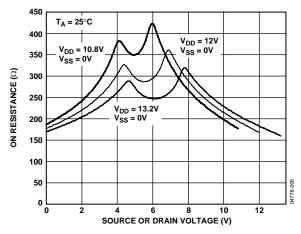


Figure 6. On Resistance as a Function of  $V_D$  ( $V_S$ ) for Single Supply

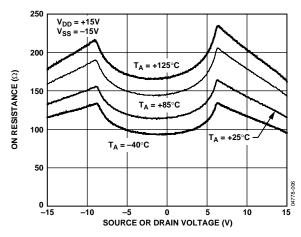


Figure 7. On Resistance as a Function of V<sub>D</sub> (V<sub>s</sub>) for Different Temperatures, Dual Supply

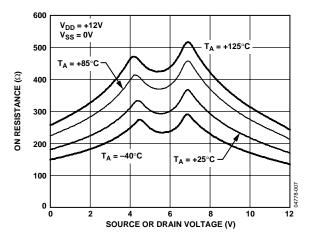


Figure 8. On Resistance as a Function of  $V_D$  ( $V_S$ ) for Different Temperatures, Single Supply

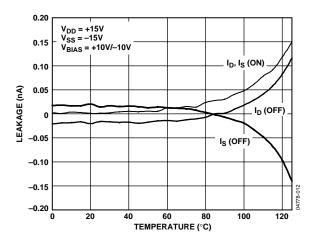


Figure 9. Leakage Currents as a Function of Temperature, Dual Supply

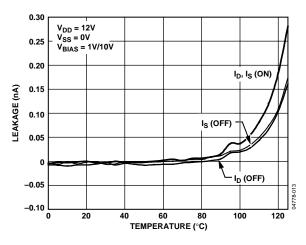
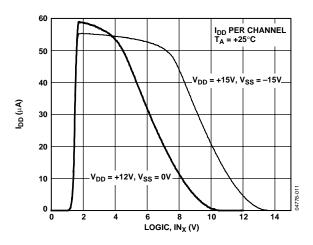


Figure 10. Leakage Currents as a Function of Temperature, Single Supply





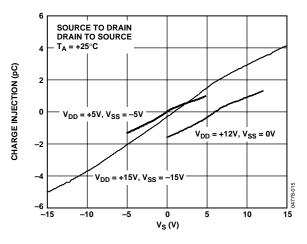


Figure 12. Charge Injection vs. Source Voltage

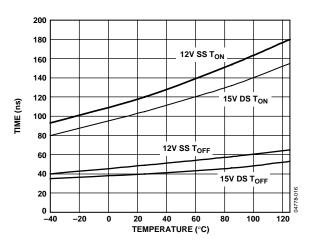
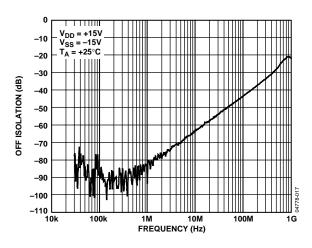


Figure 13. TON/TOFF Times vs. Temperature





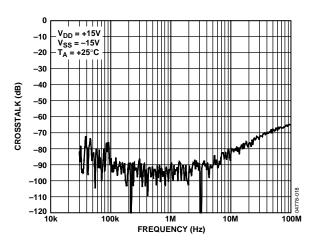
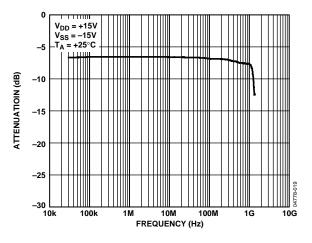
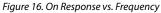


Figure 15. Crosstalk vs. Frequency





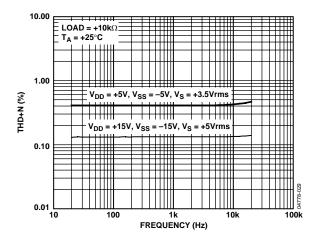


Figure 17. THD + N vs. Frequency

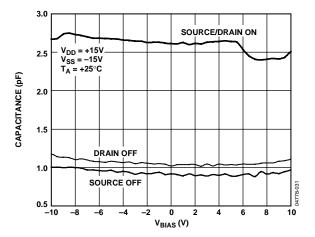


Figure 18. Capacitance vs. Source Voltage, Dual Supply

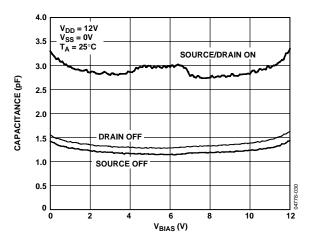
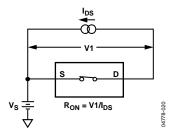


Figure 19. Capacitance vs. Source Voltage, Single Supply

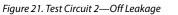
### **TEST CIRCUITS**



 $v_{s} = v_{b}$ 

NC  $\circ$  S  $\circ$  D A  $V_D = V_D$ 

Figure 20. Test Circuit 1—On Resistance





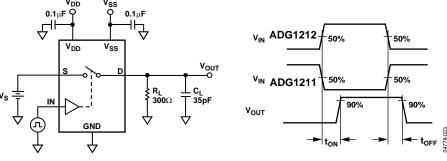


Figure 23. Test Circuit 4—Switching Times

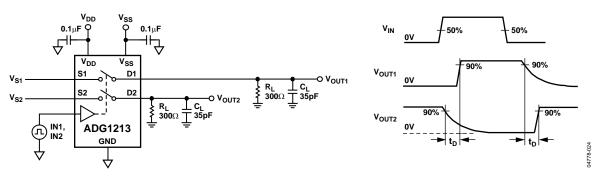


Figure 24. Test Circuit 5—Break-Before-Make Time Delay

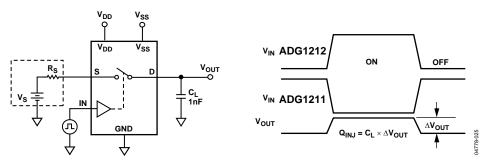


Figure 25. Test Circuit 6—Charge Injection

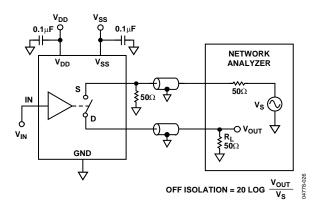


Figure 26. Test Circuit 7—Off Isolation

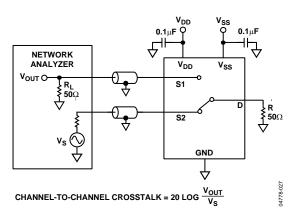


Figure 27. Test Circuit 8—Channel-to-Channel Crosstalk

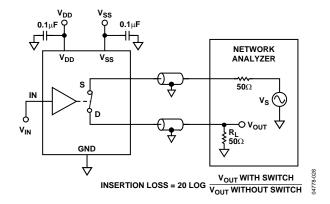


Figure 28. Test Circuit 9—Bandwidth

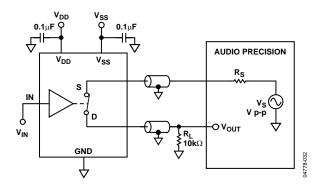
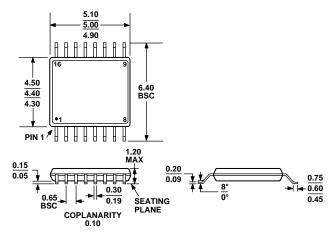


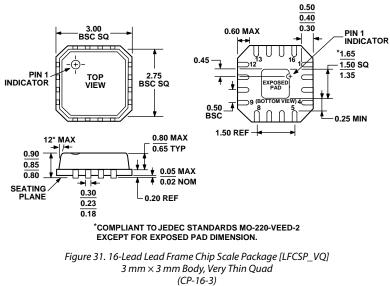
Figure 29. Test Circuit 10—THD + Noise

### **OUTLINE DIMENSIONS**



COMPLIANT TO JEDEC STANDARDS MO-153AB

Figure 30. 16-Lead Thin Shrink Small Outline Package [TSSOP] (RU-16) Dimensions shown in millimeters



Dimensions shown in millimeters

#### **ORDERING GUIDE**

Model	Temperature Range	Package Description	Package Option
ADG1211YRUZ <sup>1</sup>	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1211YRUZ-REEL <sup>1</sup>	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1211YRUZ-REEL71	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1211YCPZ-500RL71	-40°C to +125°C	Lead Frame Chip Scale Package (LFCSP_VQ)	CP-16-3
ADG1211YCPZ-REEL71	-40°C to +125°C	Lead Frame Chip Scale Package (LFCSP_VQ)	CP-16-3
ADG1212YRUZ <sup>1</sup>	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1212YRUZ-REEL <sup>1</sup>	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1212YRUZ-REEL71	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1212YCPZ-500RL71	-40°C to +125°C	Lead Frame Chip Scale Package (LFCSP_VQ)	CP-16-3
ADG1212YCPZ-REEL71	-40°C to +125°C	Lead Frame Chip Scale Package (LFCSP_VQ)	CP-16-3
ADG1213YRUZ <sup>1</sup>	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1213YRUZ-REEL <sup>1</sup>	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1213YRUZ-REEL71	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1213YCPZ-500RL71	-40°C to +125°C	Lead Frame Chip Scale Package (LFCSP_VQ)	CP-16-3
ADG1213YCPZ-REEL71	-40°C to +125°C	Lead Frame Chip Scale Package (LFCSP_VQ)	CP-16-3

 $^{1}$  Z = Pb-free part.

### NOTES



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